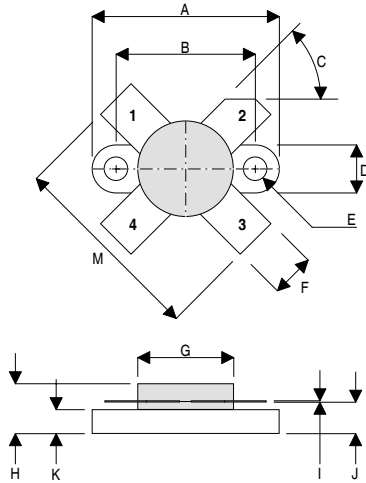


METAL GATE RF SILICON FET

MECHANICAL DATA



DM

PIN 1 SOURCE PIN 2 DRAIN
PIN 3 SOURCE PIN 4 GATE

DIM	mm	Tol.	Inches	Tol.
A	24.76	0.13	0.975	0.005
B	18.42	0.13	0.725	0.005
C	45°	5°	45°	5°
D	6.35	0.13	0.25	0.005
E	3.17 Dia.	0.13	0.125 Dia.	0.005
F	5.71	0.13	0.225	0.005
G	12.7 Dia.	0.13	0.500 Dia.	0.005
H	6.60	REF	0.260	REF
I	0.13	0.02	0.005	0.001
J	4.32	0.13	0.170	0.005
K	3.17	0.13	0.125	0.005
M	26.16	0.25	1.03	0.010

**GOLD METALIZED
MULTI-PURPOSE SILICON
DMOS RF FET
150W – 28V – 175MHz
SINGLE ENDED**

FEATURES

- SIMPLIFIED AMPLIFIER DESIGN
- SUITABLE FOR BROAD BAND APPLICATIONS
- LOW C_{rss}
- SIMPLE BIAS CIRCUITS
- LOW NOISE
- HIGH GAIN – 13 dB MINIMUM

APPLICATIONS

- HF/VHF/UHF COMMUNICATIONS
from 1 MHz to 200 MHz

ABSOLUTE MAXIMUM RATINGS ($T_{case} = 25^{\circ}C$ unless otherwise stated)

P_D	Power Dissipation	220W
BV_{DSS}	Drain – Source Breakdown Voltage	70V
BV_{GSS}	Gate – Source Breakdown Voltage	$\pm 20V$
$I_{D(sat)}$	Drain Current	30A
T_{stg}	Storage Temperature	-65 to 150°C
T_j	Maximum Operating Junction Temperature	200°C

ELECTRICAL CHARACTERISTICS ($T_{case} = 25^{\circ}\text{C}$ unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV_{DSS} Drain-Source Breakdown Voltage	$V_{GS} = 0$ $I_D = 100\text{mA}$	70			V
I_{DSS} Zero Gate Voltage Drain Current	$V_{DS} = 28\text{V}$ $V_{GS} = 0$			6	mA
I_{GSS} Gate Leakage Current	$V_{GS} = 20\text{V}$ $V_{DS} = 0$			1	μA
$V_{GS(th)}$ Gate Threshold Voltage*	$I_D = 10\text{mA}$ $V_{DS} = V_{GS}$	1		7	V
g_{fs} Forward Transconductance*	$V_{DS} = 10\text{V}$ $I_D = 6\text{A}$	4.8			S
G_{PS} Common Source Power Gain	$P_O = 150\text{W}$	13			dB
η Drain Efficiency	$V_{DS} = 28\text{V}$ $I_{DQ} = 0.6\text{A}$	50			%
VSWR Load Mismatch Tolerance	$f = 175\text{MHz}$	20:1			—
C_{iss} Input Capacitance	$V_{DS} = 0\text{V}$ $V_{GS} = -5\text{V}$ $f = 1\text{MHz}$			360	pF
C_{oss} Output Capacitance	$V_{DS} = 28\text{V}$ $V_{GS} = 0$ $f = 1\text{MHz}$			180	pF
C_{rss} Reverse Transfer Capacitance	$V_{DS} = 28\text{V}$ $V_{GS} = 0$ $f = 1\text{MHz}$			15	pF

* Pulse Test: Pulse Duration = 300 μs , Duty Cycle $\leq 2\%$

HAZARDOUS MATERIAL WARNING

The ceramic portion of the device between leads and metal flange is beryllium oxide. Beryllium oxide dust is highly toxic and care must be taken during handling and mounting to avoid damage to this area.

THESE DEVICES MUST NEVER BE THROWN AWAY WITH GENERAL INDUSTRIAL OR DOMESTIC WASTE.

THERMAL DATA

$R_{THj-case}$	Thermal Resistance Junction – Case	Max. 0.8°C / W
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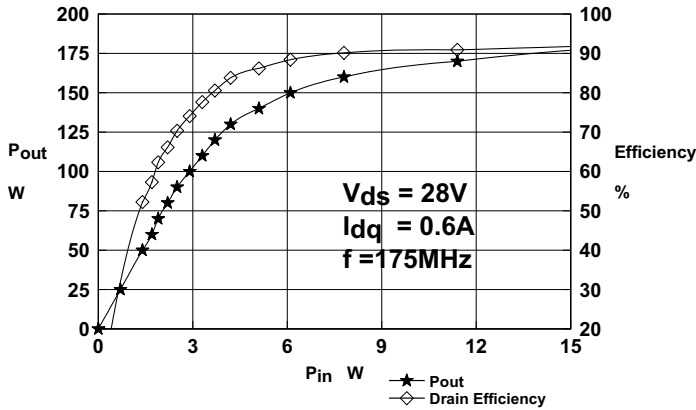


Figure 1

Power Out & Efficiency vs Power Input

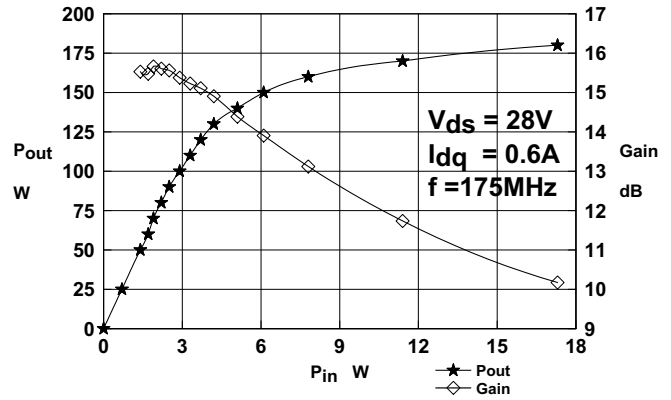


Figure 2

Power Out & Gain vs. Power Input

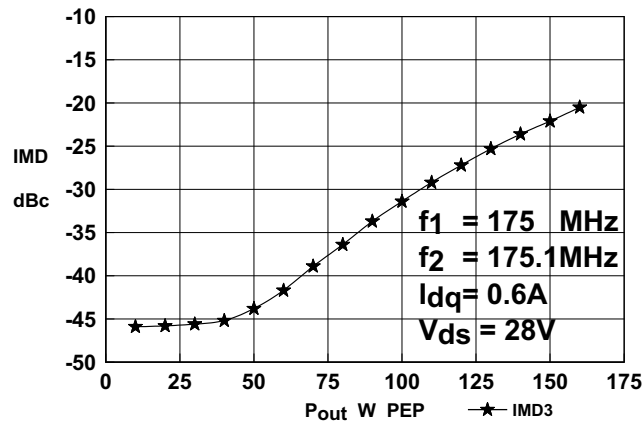


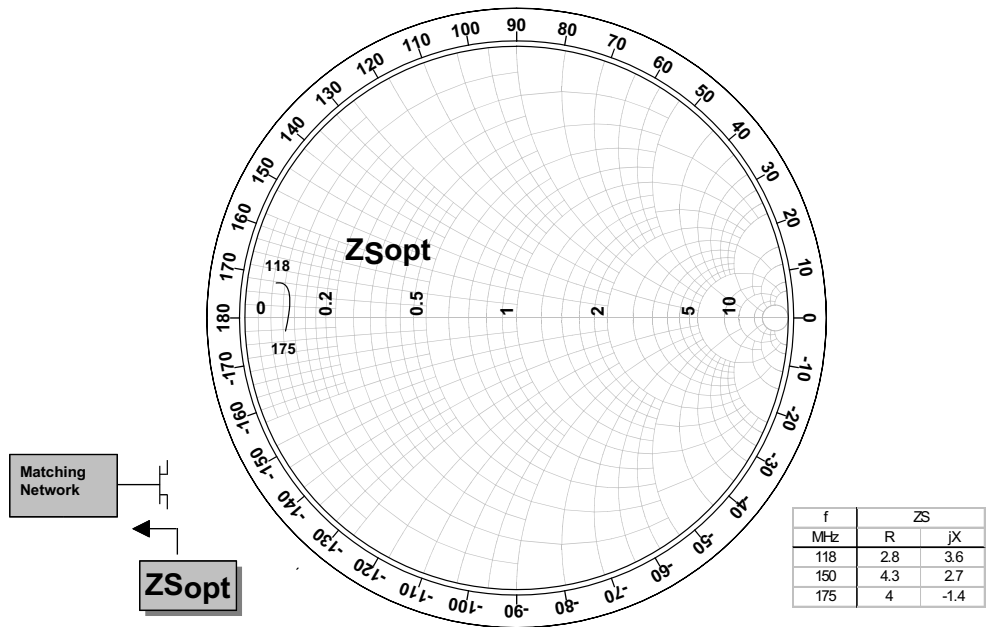
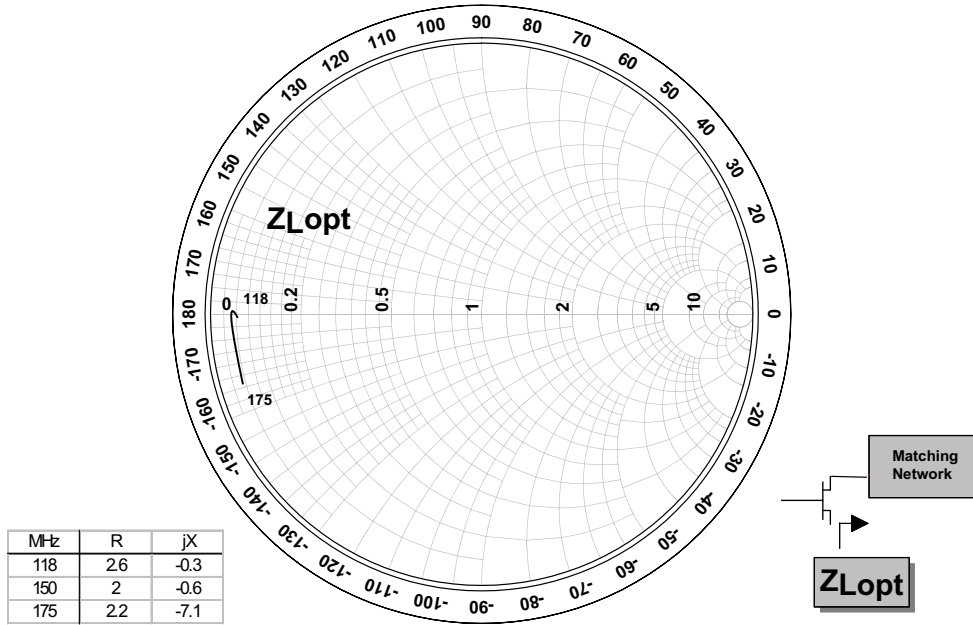
Figure 3

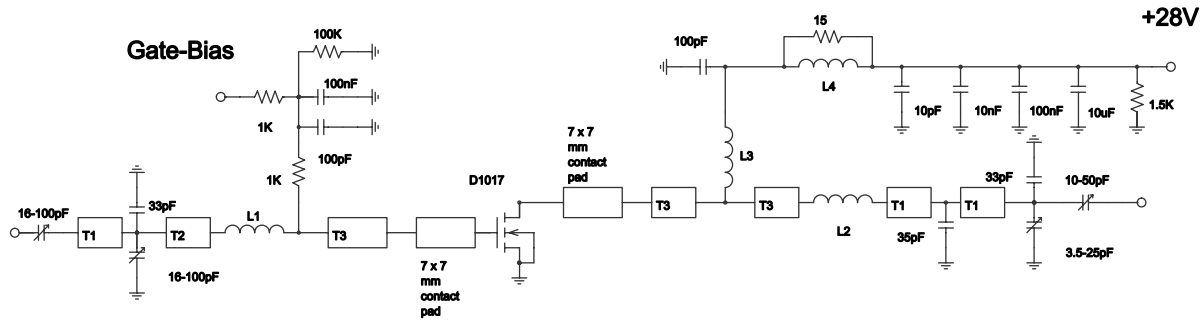
IMD Versus Power Output

Typical S Parameters

! V_{ds}=28V I_{dq}=0.6A
MHZ S MA R 50

!Freq !MHz	S11		S21		S12		S22	
	mag	ang	mag	ang	mag	ang	mag	ang
50	0.83	-167.4	7.42	93.3	0.009	26.5	0.79	-167
100	0.89	-169.4	3.56	64.1	0.008	44.1	0.82	-163.7
150	0.93	-169.3	2.05	45.2	0.01	75.4	0.87	-164.7
200	0.95	-170.1	1.23	34.2	0.016	88.2	0.91	-166.3
250	0.96	-170.2	0.85	26	0.023	89.1	0.94	-167.7
300	0.97	-169.7	0.62	22.6	0.03	90.1	0.96	-169
350	0.97	-170.4	0.44	15.2	0.035	86.1	0.96	-169.8
400	0.98	-169.3	0.35	17.8	0.043	85.2	0.97	-170.5
450	0.98	-169	0.27	15.9	0.046	84	0.98	-171.7
500	0.99	-168.5	0.23	19.6	0.053	83.1	0.99	-171.4





175MHz TEST FIXTURE

Substrate 1.6mm PTFE/glass, $\epsilon_r=2.5$

All microstrip lines $W = 5\text{mm}$

T1,T2 7.5mm

T3 6mm

L1 Hairpin loop 18swg 10mm high, 6.5mm gap

L2 Hairpin loop 5mm wide ribbon, 7mm high, 3.5mm gap

L3 9 turns 19swg enamelled copper wire, 6mm i.d.

L4 12 turns 19swg enamelled copper wire on Fair-Rite FT82 ferrite core

*D1017

*PSPICE MODEL FOR POINT NINE RF N-CHANNEL VERTICAL DMOS POWER FET

*May 2004

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*          _____GATE
*          I   _____DRAIN
*          I   I   _____SOURCE
*          I   I   I
.SUBCKT D1017  10  20  30
*Cin1,Cin2 & Lin model the input side of the package
Cin1  10   30   0.45p
Lin   10   11   0.68n
Cin2  11   30   0.45p
LG    11   12   0.2n   ;Gate bond wire inductance
CGS   12   13   276p   ;Gate-source capacitance
MOS   14   12   13     13  D1017 L=0.9U W=0.336   ;D G S B LEVEL1
JFET  16   13   14     D1017                       ;D G S
DBODY 13   16   D1017                                   ;P N
LS    13   30   0.4n   ;Source bond wire inductance
CGD   12   16   6p     ;Gate-drain feedback capacitance

*Cout1,Cout2 & Lout model the output side of the package
Cout1  16   30   1.2p
Lout   16   20   1.68n
Cout2  20   30   1.2p

.MODEL D1017  NMOS (VTO=4.76 KP=2.811E-5 LAMBDA=0.032 RD=0.013 RS=0.051)
.MODEL D1017  NJF  (VTO=-4.3 BETA=1.5 LAMBDA=0.54)
.MODEL D1017  D    (CJO=493.2P RS=0.25 VJ=0.7 M=0.35 BV=75)

.ENDS
```